

SN54LV165, SN74LV165 PARALLEL-LOAD 8-BIT SHIFT REGISTERS

SCES007B – MARCH 1995 – REVISED APRIL 1996

- **EPIC™ (Enhanced-Performance Implanted CMOS) 2- μ Process**
- **Typical V_{OLP} (Output Ground Bounce) < 0.8 V at V_{CC} , $T_A = 25^\circ\text{C}$**
- **Typical V_{OHV} (Output V_{OH} Undershoot) < 2 V at V_{CC} , $T_A = 25^\circ\text{C}$**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model ($C = 200$ pF, $R = 0$)**
- **Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17**
- **Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), Ceramic Flat (W) Packages, Chip Carriers (FK), and (J) 300-mil DIPs**

description

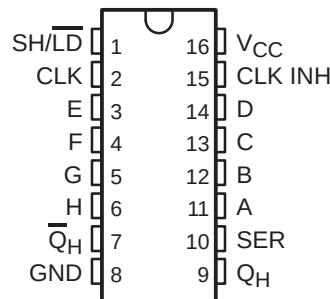
The 'LV165 parallel-load, 8-bit shift registers are designed for 2.7-V to 5.5-V V_{CC} operation.

When the device is clocked, data is shifted toward the serial output Q_H . Parallel-in access to each stage is provided by eight individual direct data inputs that are enabled by a low level at the $SH/\overline{LD}$ input. The 'LV165 feature a clock inhibit function and a complemented serial output $\overline{Q}_H$.

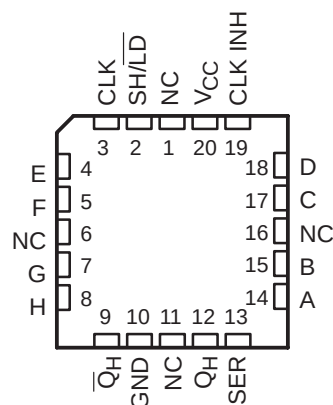
Clocking is accomplished by a low-to-high transition of the clock (CLK) input while $SH/\overline{LD}$ is held high and clock inhibit (CLK INH) is held low. The functions of the CLK and CLK INH inputs are interchangeable. Since a low CLK input and a low-to-high transition of CLK INH accomplishes clocking, CLK INH should be changed to the high level only while CLK is high. Parallel loading is inhibited when $SH/\overline{LD}$ is held high. The parallel inputs to the register are enabled while $SH/\overline{LD}$ is held low independently of the levels of CLK, CLK INH, or SER.

The SN54LV165 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74LV165 is characterized for operation from -40°C to 85°C .

SN54LV165 . . . J OR W PACKAGE
SN74LV165 . . . D, DB, OR PW PACKAGE
(TOP VIEW)



SN54LV165 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

FUNCTION TABLE

INPUTS			OPERATION
$SH/\overline{LD}$	CLK	CLK INH	
L	X	X	Parallel load
H	H	X	Q_0
H	X	H	Q_0
H	L	$\uparrow$	Shift
H	$\uparrow$	L	Shift



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**TEXAS
INSTRUMENTS**

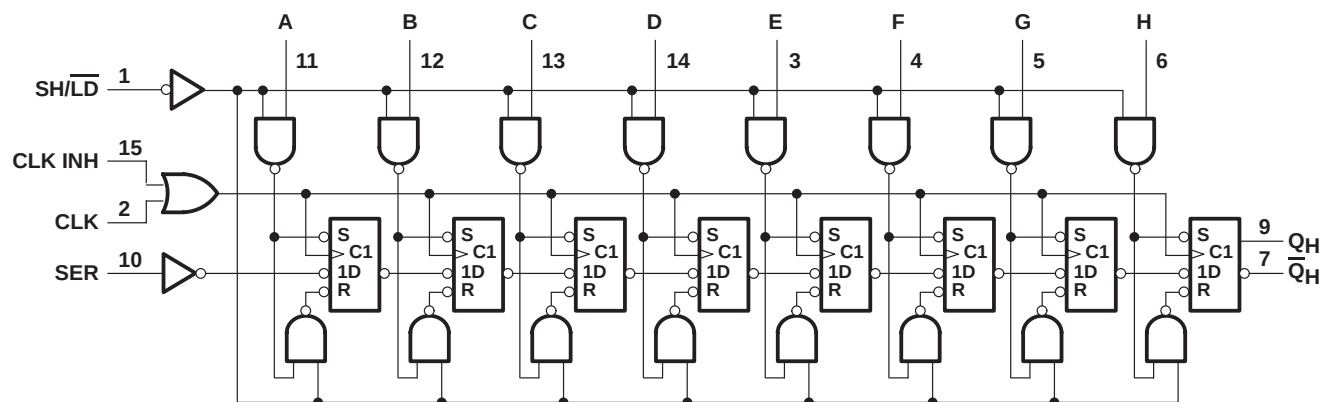
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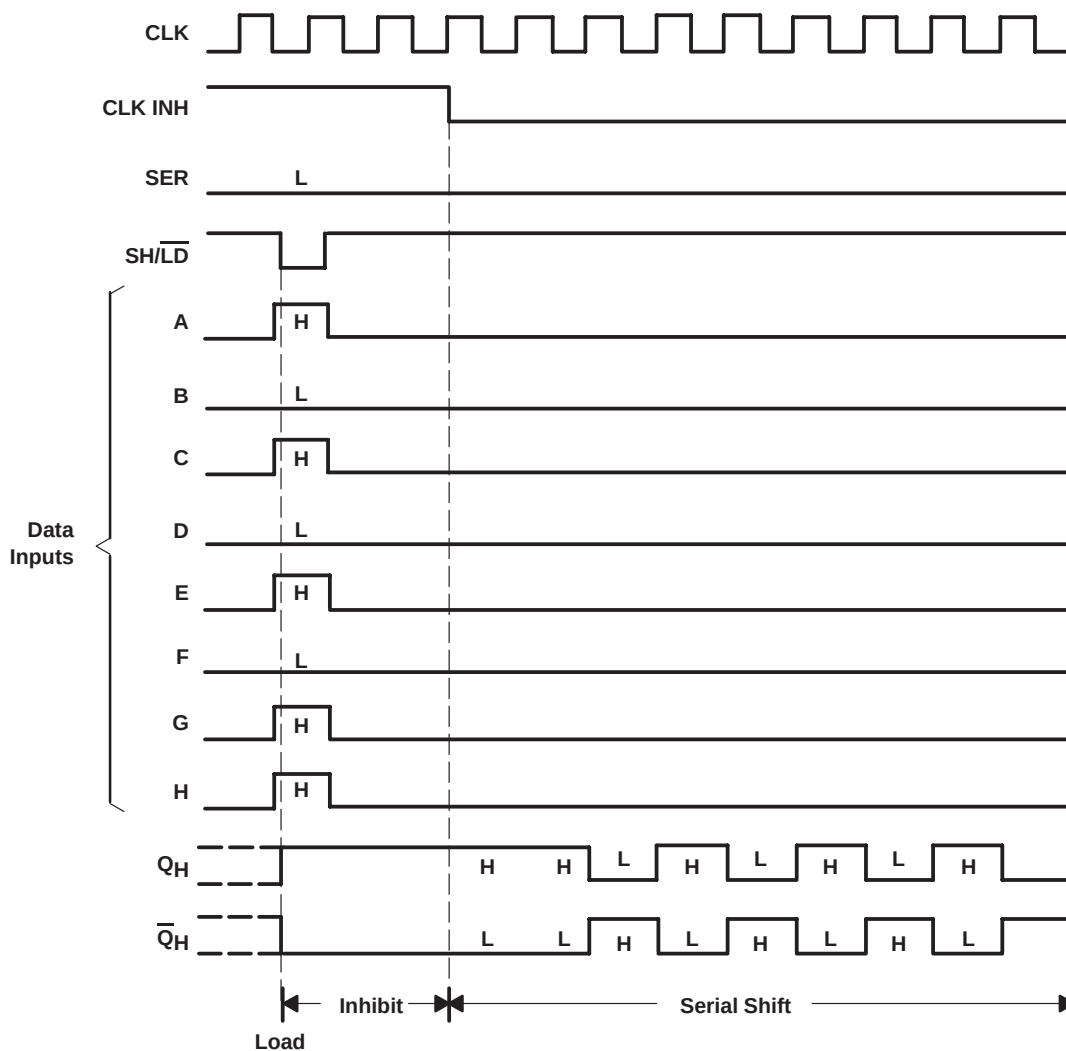
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logic diagram (positive logic)



Pin numbers shown are for D, DB, J, PW, and W packages.

typical shift, load, and inhibit sequences



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	± 20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	± 50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	± 25 mA
Continuous current through V_{CC} or GND	± 50 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see Note 3):	
D package	1.30 W
DB package	0.55 W
PW package	0.5 W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 7 V maximum.
 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

recommended operating conditions (see Note 4)

			SN54LV165		SN74LV165		UNIT
			MIN	MAX	MIN	MAX	
V _{CC}	Supply voltage		2.7	5.5	2.7	5.5	V
V _{IH}	High-level input voltage	V _{CC} = 2.7 V to 3.6 V	2		2		V
		V _{CC} = 4.5 V to 5.5 V	3.15		3.15		
V _{IL}	Low-level input voltage	V _{CC} = 2.7 V to 3.6 V	0.8		0.8		V
		V _{CC} = 4.5 V to 5.5 V	1.65		1.65		
V _I	Input voltage		0	V _{CC}	0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 2.7 V to 3.6 V	−6		−6		mA
		V _{CC} = 4.5 V to 5.5 V	−12		−12		
I _{OL}	Low-level output current	V _{CC} = 2.7 V to 3.6 V	6		6		mA
		V _{CC} = 4.5 V to 5.5 V	12		12		
Δt/Δv	Input transition rise or fall rate		0	100	0	100	ns/V
T _A	Operating free-air temperature		−55	125	−40	85	°C

NOTE 4: Unused inputs must be held high or low to prevent them from floating.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC} [†]	SN54LV165			SN74LV165			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	
V _{OH}	I _{OH} = −100 μA	MIN to MAX	V _{CC} −0.2			V _{CC} −0.2			V
	I _{OH} = −6 mA	3 V	2.4			2.4			
	I _{OH} = −12 mA	4.5 V	3.6			3.6			
V _{OL}	I _{OL} = 100 μA	MIN to MAX	0.2			0.2			V
	I _{OL} = 6 mA	3 V	0.4			0.4			
	I _{OL} = 12 mA	4.5 V	0.55			0.55			
I _I	V _I = V _{CC} or GND	3.6 V	±1			±1			μA
		5.5 V	±1			±1			
I _{CC}	V _I = V _{CC} or GND, I _O = 0	3.6 V	20			20			μA
		5.5 V	20			20			
ΔI _{CC}	One input at V _{CC} − 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	500			500			μA
C _i	V _I = V _{CC} or GND	3.3 V	2.5			2.5			pF
		5 V	3			3			

$\dagger$ For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

			SN54LV165						UNIT
			$V_{CC} = 5.5\text{ V} \pm 0.5\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		$V_{CC} = 2.7\text{ V}$		
			MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		0	50	0	40	0	30	MHz
t _w	Pulse duration	CLK high or low	14		18		22		ns
		SH/LD low	14		18		22		
t _{su}	Setup time	SH/LD high before CLK↑	10		13		17		ns
		SER before CLK↑	8		11		14		
		CLK INH before CLK↑	10		12		15		
		Data before SH/LD↑	8		12		17		
t _h	Hold time	SER data after CLK↑	6		6		5		ns
		Parallel data after SH/LD↑	6		6		5		

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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

			SN74LV165						UNIT
			$V_{CC} = 5.5\text{ V}$ $\pm 0.5\text{ V}$		$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$		$V_{CC} = 2.7\text{ V}$		
			MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		0	50	0	40	0	30	MHz
t _w	Pulse duration	CLK high or low	14		18		22		ns
		SH/LD low	14		18		22		
t _{su}	Setup time	SH/LD high before CLK↑	10		13		17		ns
		SER before CLK↑	8		11		14		
		CLK INH before CLK↑	10		12		15		
		Data before SH/LD↑	8		12		17		
t _h	Hold time	SER data after CLK↑	6		6		5		ns
		Parallel data after SH/LD↑	6		6		5		

switching characteristics over recommended operating free-air temperature range, $C_L = 50\text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN54LV165								UNIT
			V _{CC} = 5.5 V ± 0.5 V			V _{CC} = 3.3 V ± 0.3 V			V _{CC} = 2.7 V		
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	MAX	
f _{max}			50	90		40	75		30		MHz
t _{pd}	CLK	Q _H or $\overline{Q}_H$		20	24		20	38		47	ns
	SH/LD			19	24		19	36		44	
	H			15	20		15	29		36	

switching characteristics over recommended operating free-air temperature range, $C_L = 50\text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN74LV165								UNIT
			V _{CC} = 5.5 V ± 0.5 V			V _{CC} = 3.3 V ± 0.3 V			V _{CC} = 2.7 V		
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	MAX	
f _{max}			50	90		40	75		30		MHz
t _{pd}	CLK	Q _H or $\overline{Q}_H$		20	24		20	38		47	ns
	SH/LD			19	24		19	36		44	
	H			15	20		15	29		36	

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS		V_{CC}	TYP	UNIT
C_{pd}	Power dissipation capacitance	$C_L = 50\text{ pF}$, $f = 10\text{ MHz}$		3.3 V	33	pF
				5 V	57	

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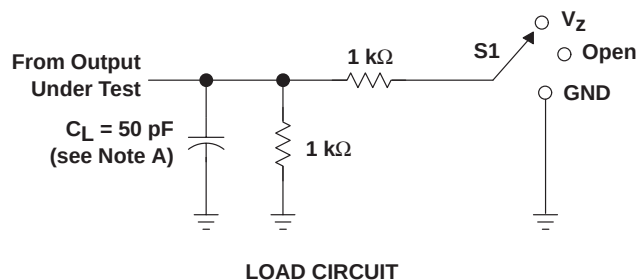


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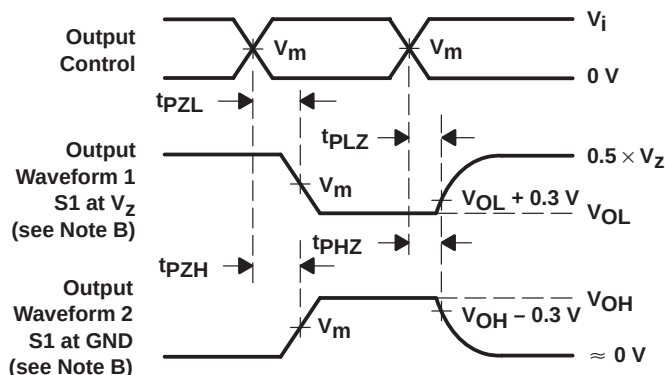
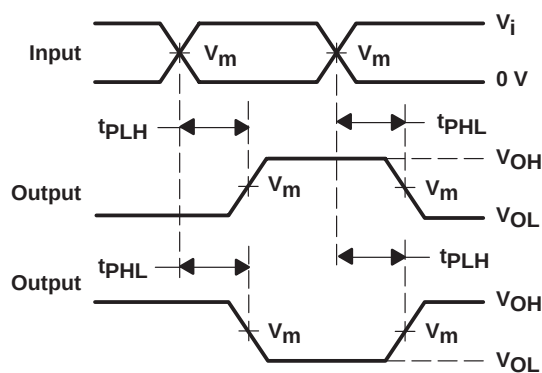
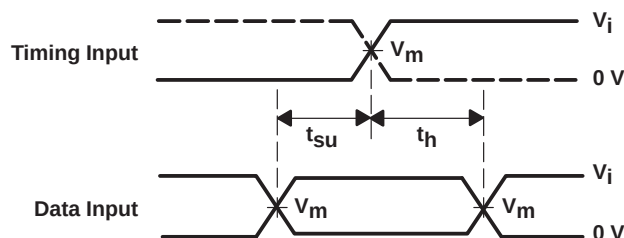
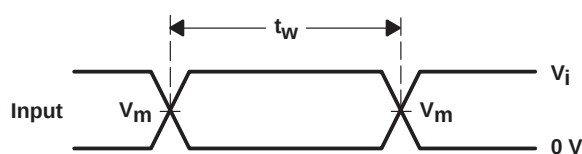
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PARAMETER MEASUREMENT INFORMATION



TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	V _Z
t_{PHZ}/t_{PZH}	GND

WAVEFORM CONDITION	V _{CC} = 4.5 V to 5.5 V	V _{CC} = 2.7 V to 3.6 V
V _m	$0.5 \times V_{CC}$	1.5 V
V _i	V _{CC}	2.7 V
V _Z	$2 \times V_{CC}$	6 V



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: PRR $\leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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